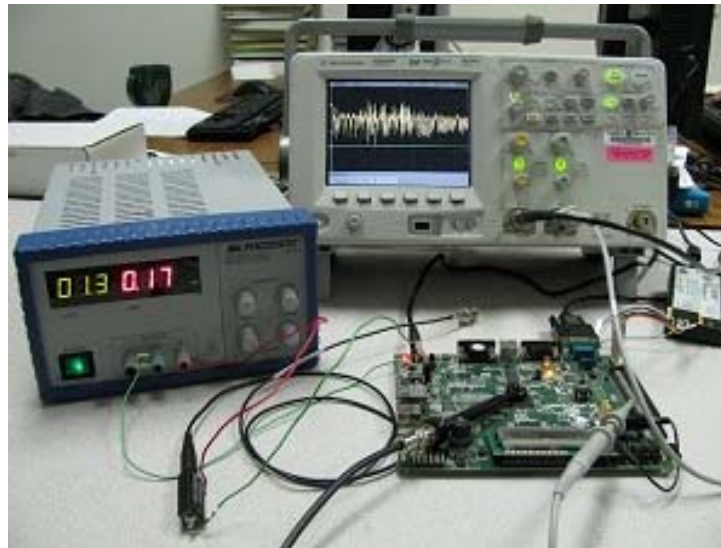


---

# How to Certify the Leakage of a Chip?



F. Durvaux, ***F.-X. Standaert***, N. Veyrat-Charvillon

UCL Crypto Group, Belgium

**EUROCRYPT 2014, Copenhagen, Denmark**

---

---

Problem statement

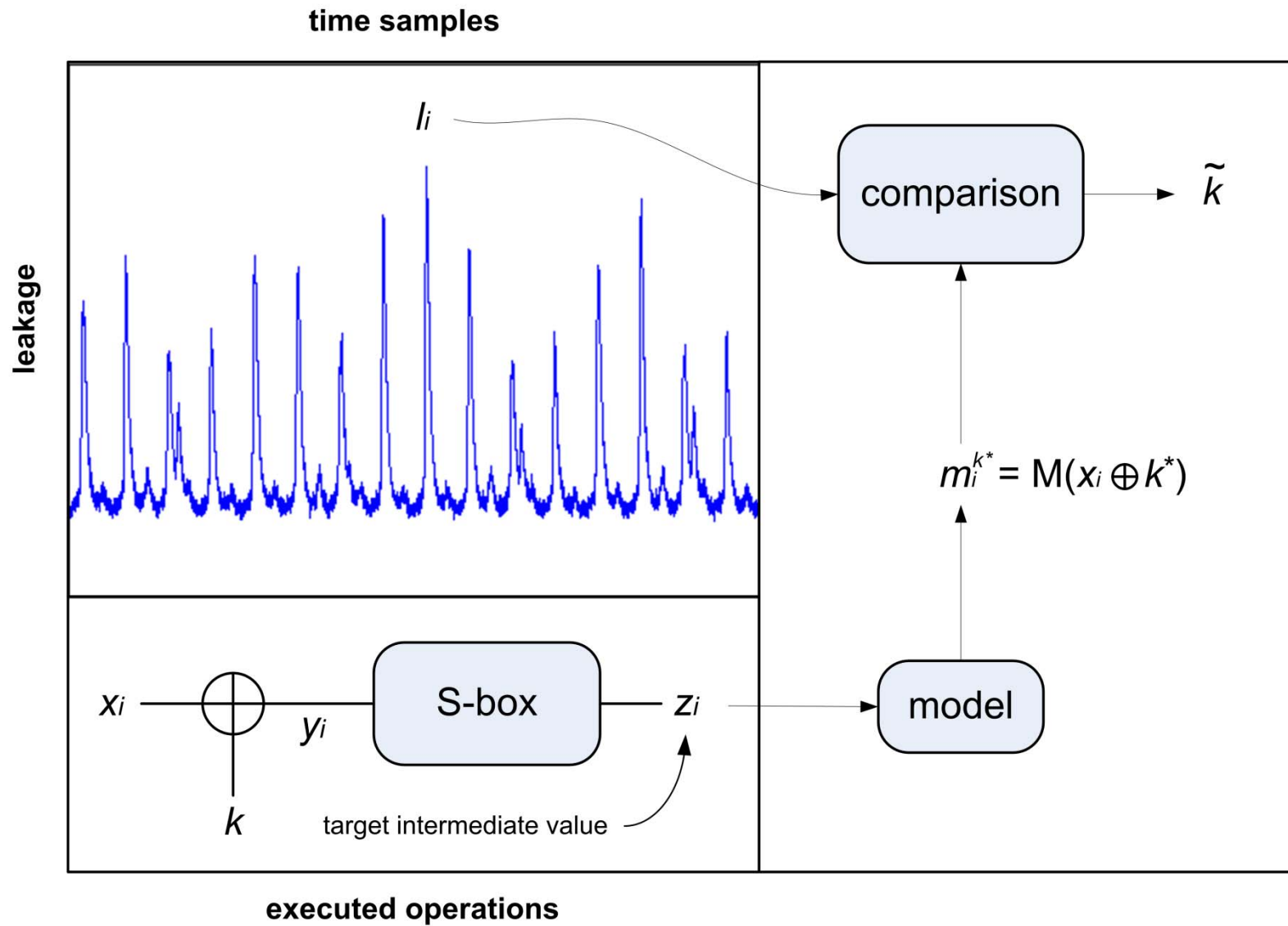
***Evaluation / certification of leaking devices***

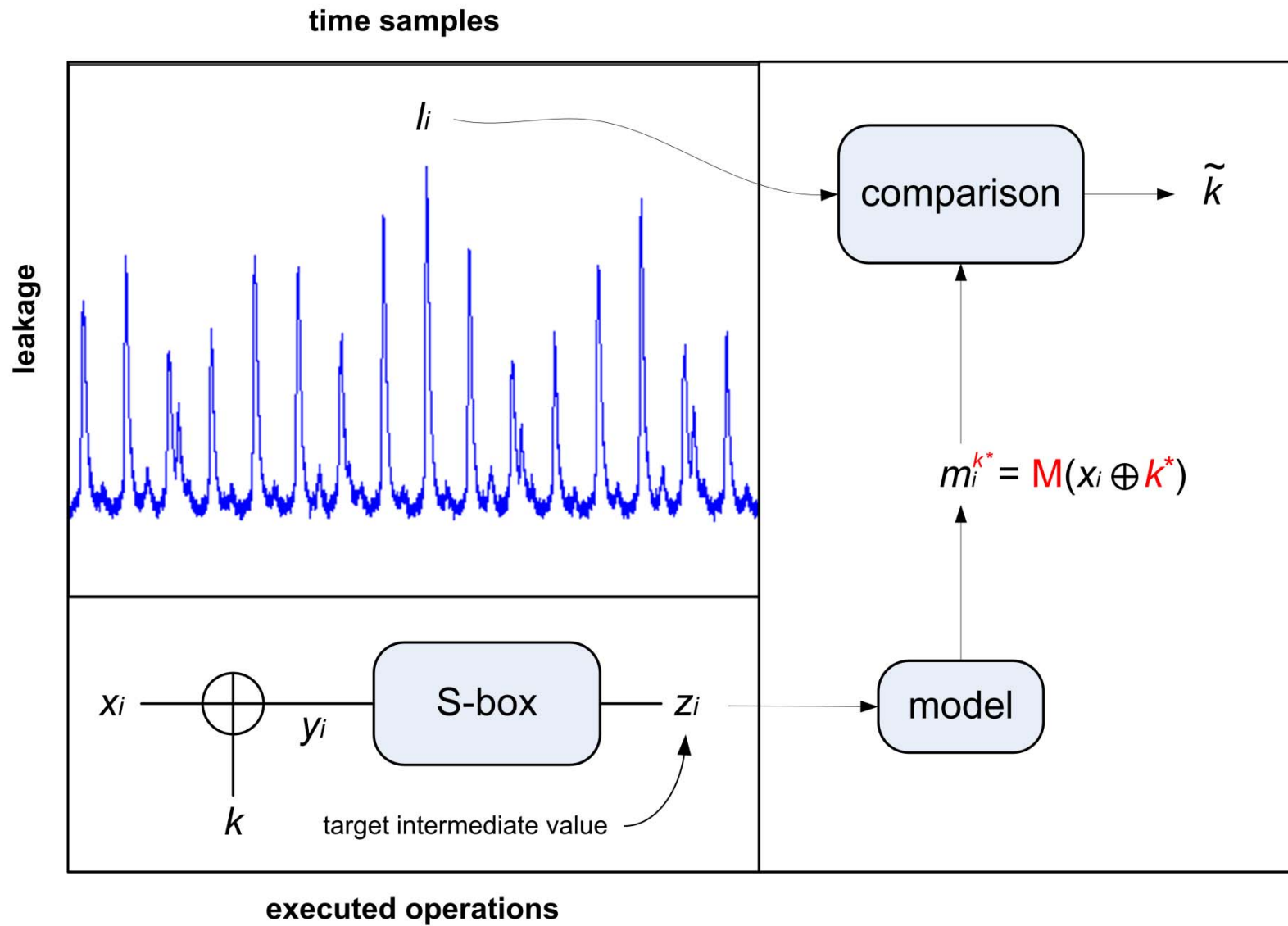
---

- We currently lack formal approaches to “prove” the security of cryptographic implementations
  - Despite progresses in leakage-resilience

- We currently lack formal approaches to “prove” the security of cryptographic implementations
  - Despite progresses in leakage-resilience
- The secure smart cards in your pockets usually go through the process of evaluation/certification
  - i.e. they are sent to a lab for evaluation and come back with a “security stamp” (A,B,C, ...)

- We currently lack formal approaches to “prove” the security of cryptographic implementations
  - Despite progresses in leakage-resilience
- The secure smart cards in your pockets usually go through the process of evaluation/certification
  - i.e. they are sent to a lab for evaluation and come back with a “security stamp” (A,B,C, ...)
- This talk is about how to perform evaluations  
=> Quantified levels rather than hard to interpret letters  
( $\approx$  compute the  $\varepsilon$ 's in proofs of leakage-resilience)





- Ideally, we should consider *worst-case* attacks



- Ideally, we should consider *worst-case* attacks
- But side-channel attacks rely on hypotheses
  - on the target piece of key (*useful*)
  - and on the leakage model (*useless*)

- Ideally, we should consider *worst-case* attacks
- But side-channel attacks rely on hypotheses
  - on the target piece of key (*useful*)
  - and on the leakage model (*useless*)

=> Worst-case evaluations require a *perfect* model

- Ideally, we should consider *worst-case* attacks
- But side-channel attacks rely on hypotheses
  - on the target piece of key (*useful*)
  - and on the leakage model (*useless*)

=> Worst-case evaluations require a *perfect* model

- Problem: such a (*physical*) model is unknown!

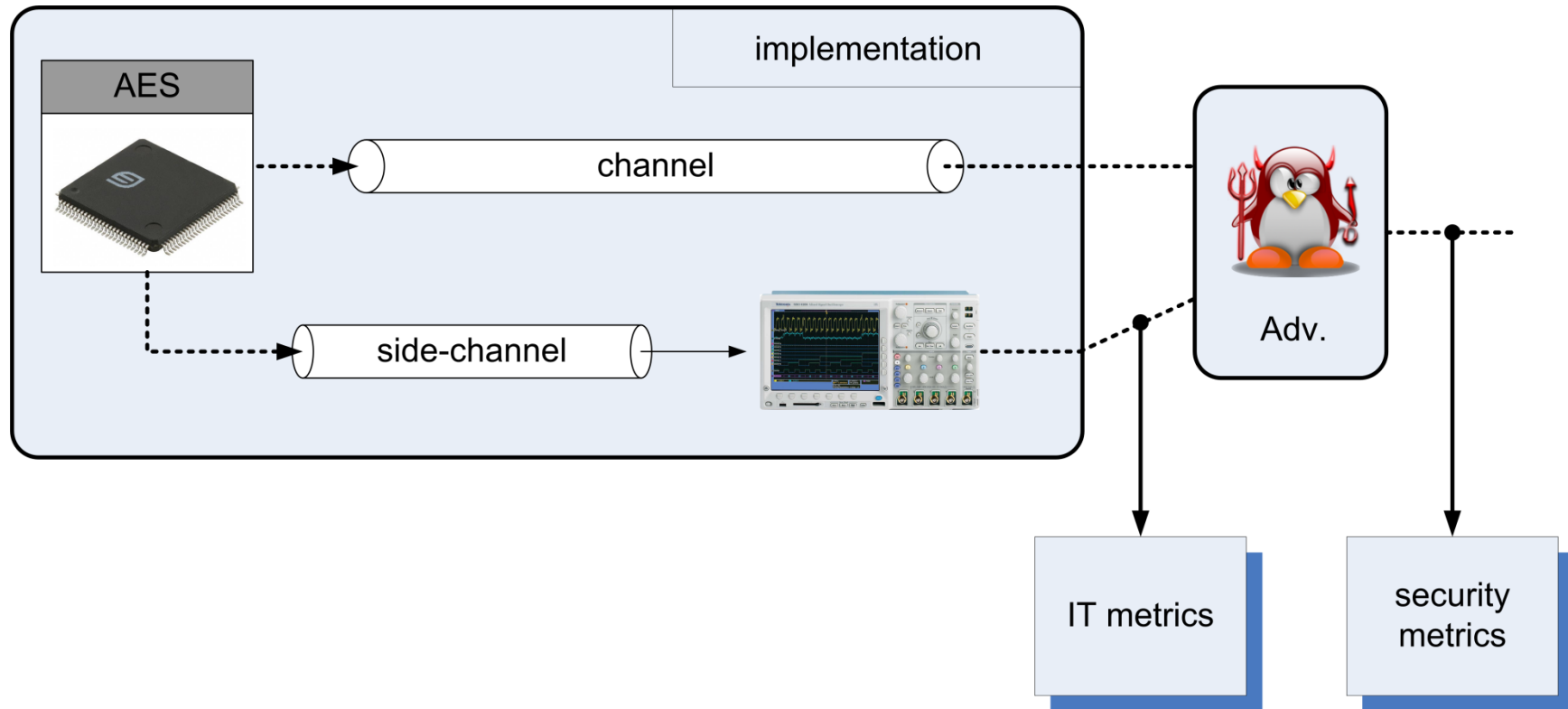
- Ideally, we should consider *worst-case* attacks
- But side-channel attacks rely on hypotheses
  - on the target piece of key (*useful*)
  - and on the leakage model (*useless*)

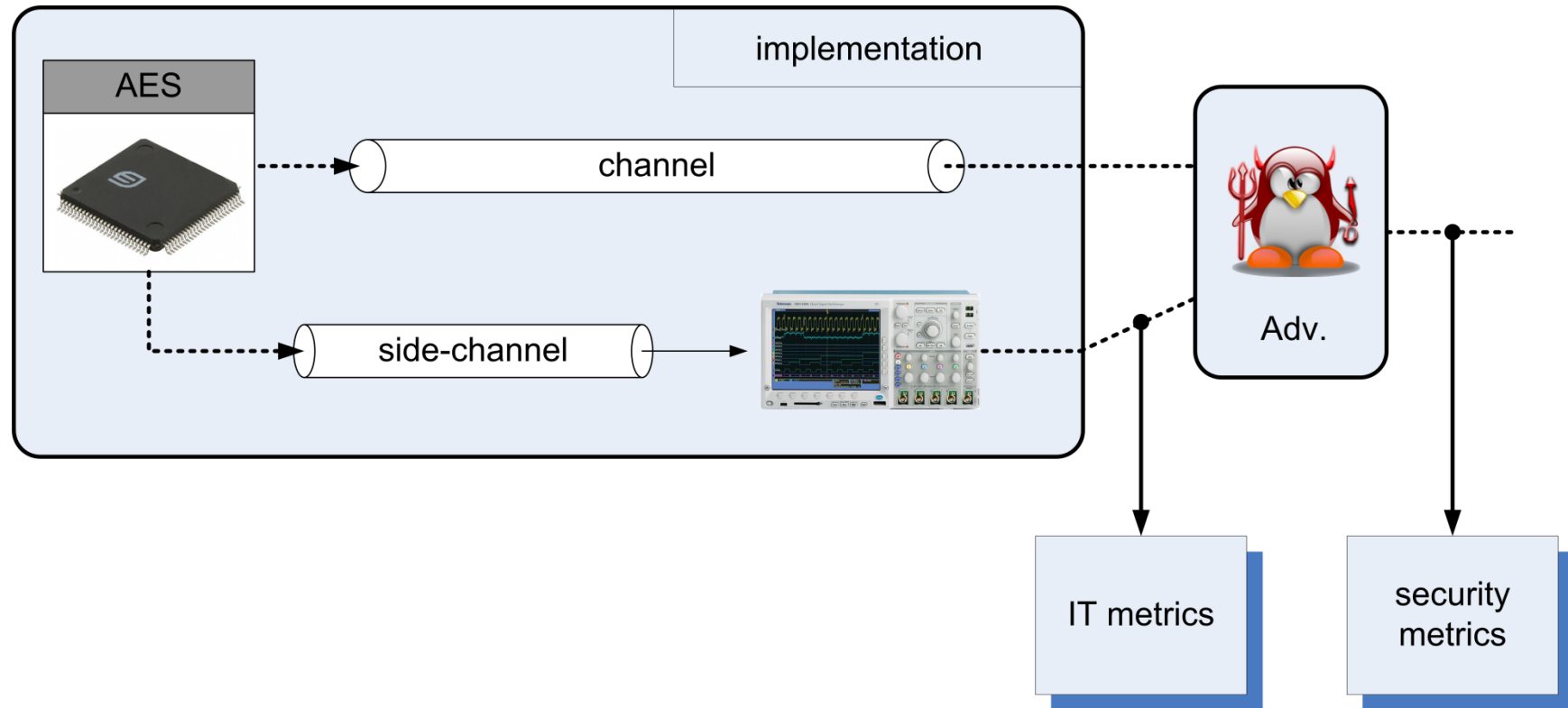
=> Worst-case evaluations require a *perfect* model

- Problem: such a (*physical*) model is unknown!
- This talk: *how good is my leakage model?*

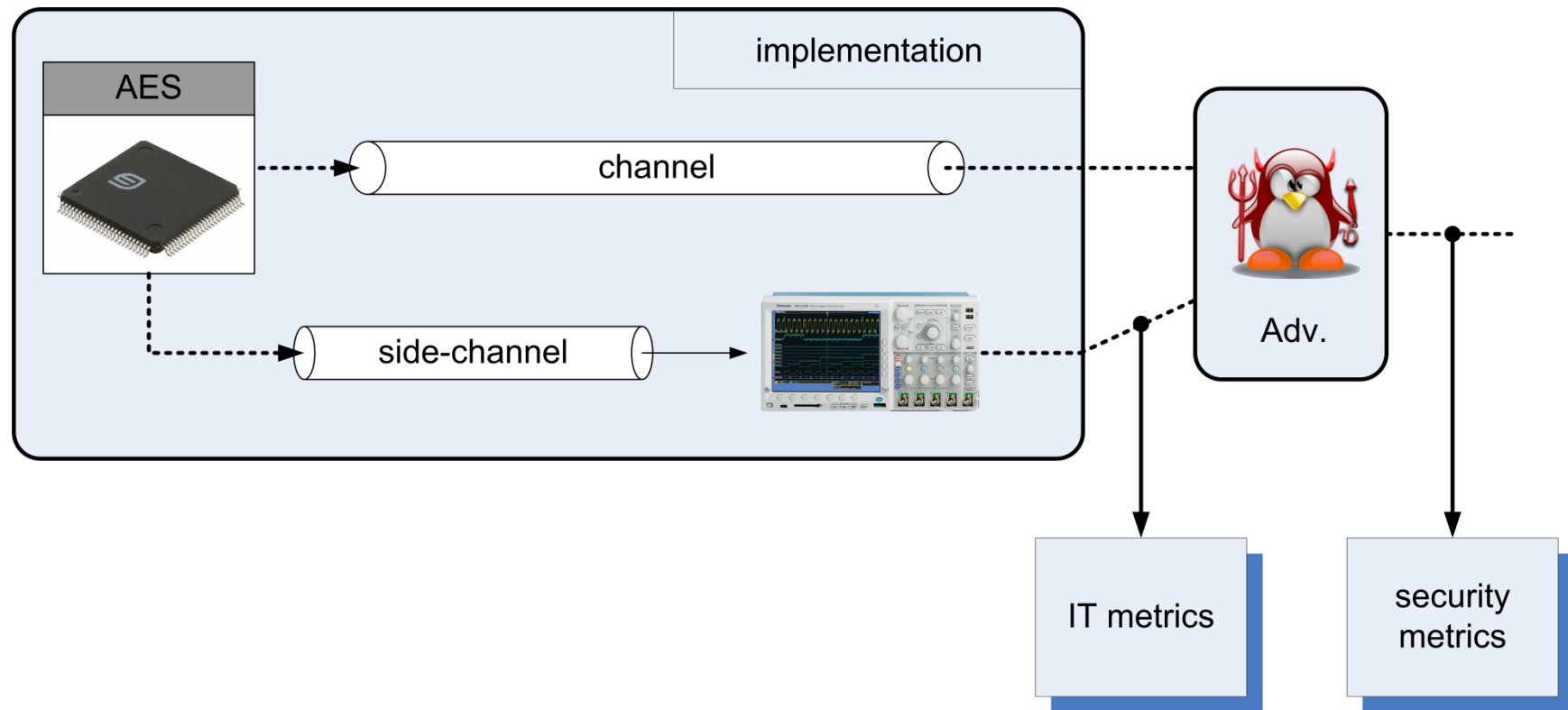
# Background: EC09 framework [1]

4

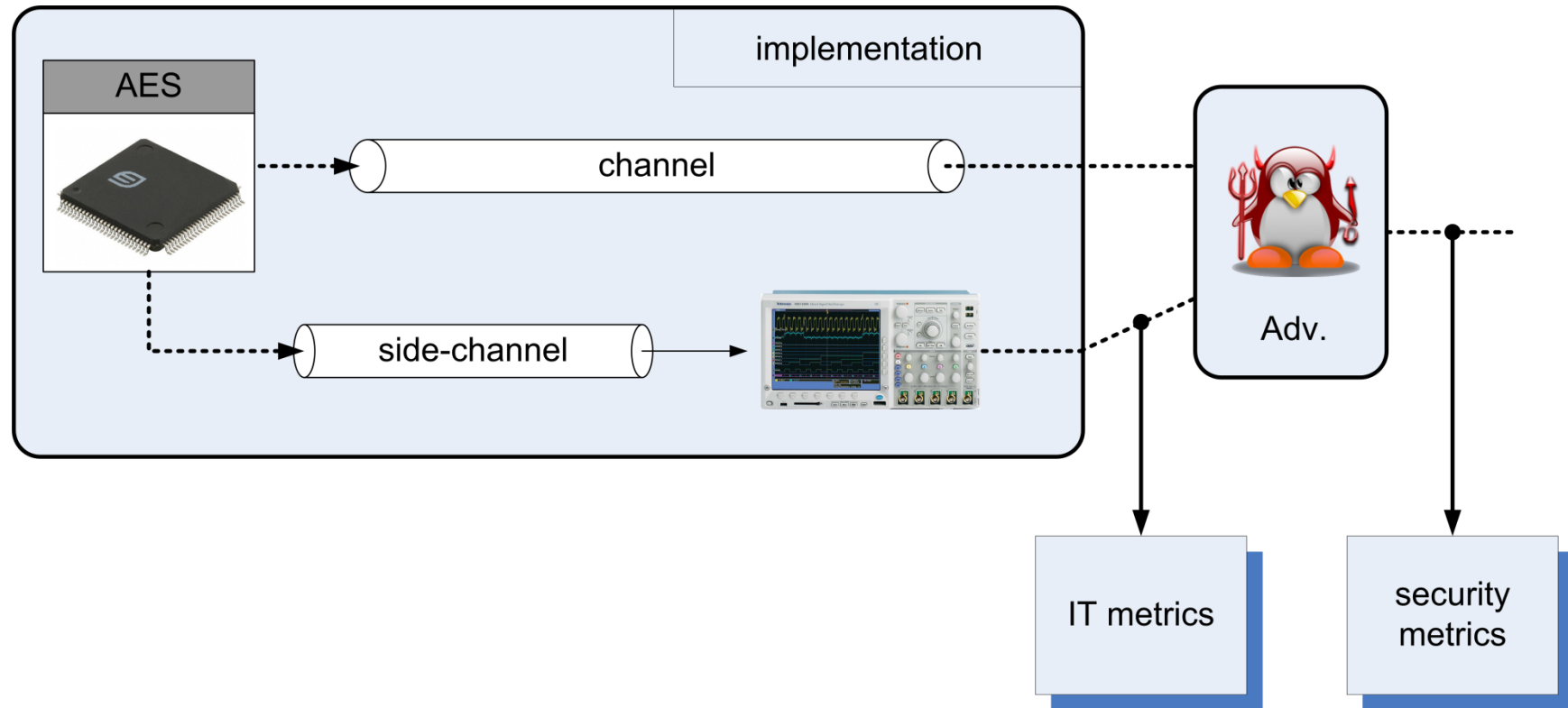




- Problem: estimating (e.g.) the mutual information between arbitrary distributions is notoriously hard!



- Good news: side-channel attacks need a **model**
  - i.e. an estimation of the leakage distribution



- Main idea: estimate the mutual information from the “best available” model (*practical worst case*)



- Information leakage on the secret key

$$H[K] - \sum_k \Pr[k] \sum_l \Pr_{chip} [l|k] \cdot \log_2 \widehat{\Pr}_{model} [k|l]$$

- where  $\widehat{\Pr}_{model} [k|l]$  is obtained by profiling
- and  $\Pr_{chip} [l|k]$  is unknown but can be sampled

- Case #1 (ideal): perfect profiling phase
- i. e.  $\widehat{\Pr}_{model} [l|k] = \Pr_{chip} [l|k]$

$$\widehat{MI}(K;L) = H[K] - \sum_k \Pr[k] \sum_l \Pr_{chip} [l|k] \cdot \log_2 \Pr_{chip} [k|l]$$

- Case #1 (ideal): perfect profiling phase
- i. e.  $\widehat{\Pr}_{model} [l|k] = \Pr_{chip} [l|k]$

$$\widehat{MI}(K;L) = H[K] - \sum_k \Pr[k] \sum_l \Pr_{chip} [l|k] \cdot \log_2 \Pr_{chip} [k|l]$$

- Case #2 (actual): bounded profiling phase
- i. e.  $\widehat{\Pr}_{model} [l|k] \neq \Pr_{chip} [l|k]$

$$\widehat{PI}(K;L) = H[K] - \sum_k \Pr[k] \sum_l \Pr_{chip} [l|k] \cdot \log_2 \widehat{\Pr}_{model} [k|l]$$

- What is the distance between the MI and the PI?  
(i.e. *how good is my leakage model?*)

- What is the distance between the MI and the PI?  
(i.e. *how good is my leakage model?*)
- Difficult since the leakage function is unknown  
=> Impossible to compute this distance directly!

- What is the distance between the MI and the PI?  
(i.e. *how good is my leakage model?*)
- Difficult since the leakage function is unknown  
=> Impossible to compute this distance directly!
- Our result: we show that indirect approaches allow answering the question quite rigorously

- What is the distance between the MI and the PI?  
(i.e. *how good is my leakage model?*)
- Difficult since the leakage function is unknown  
=> Impossible to compute this distance directly!
- Our result: we show that indirect approaches allow answering the question quite rigorously
- **Main idea: quantify the different model errors!**

---

First question: estimation errors

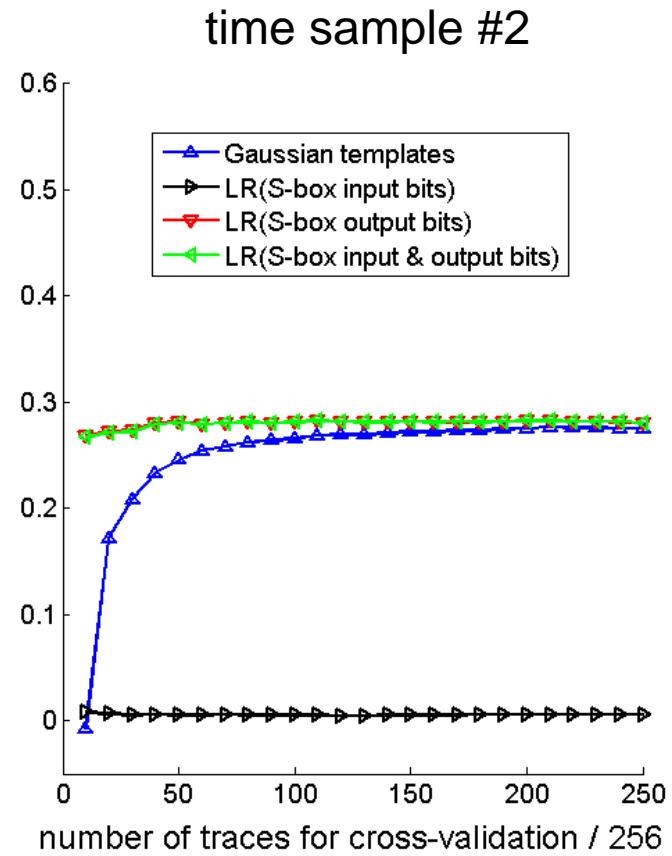
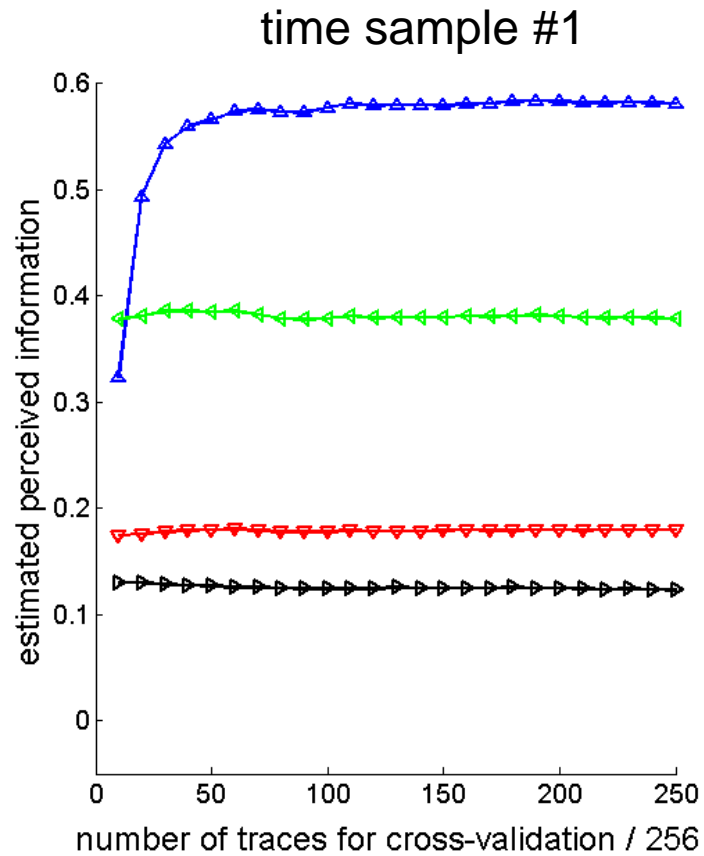
***Has my model converged?***

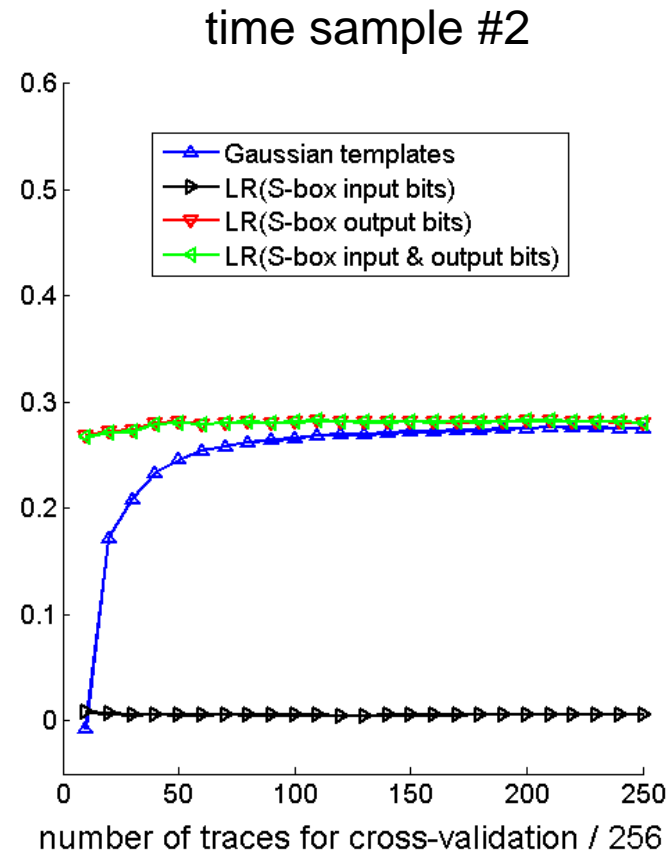
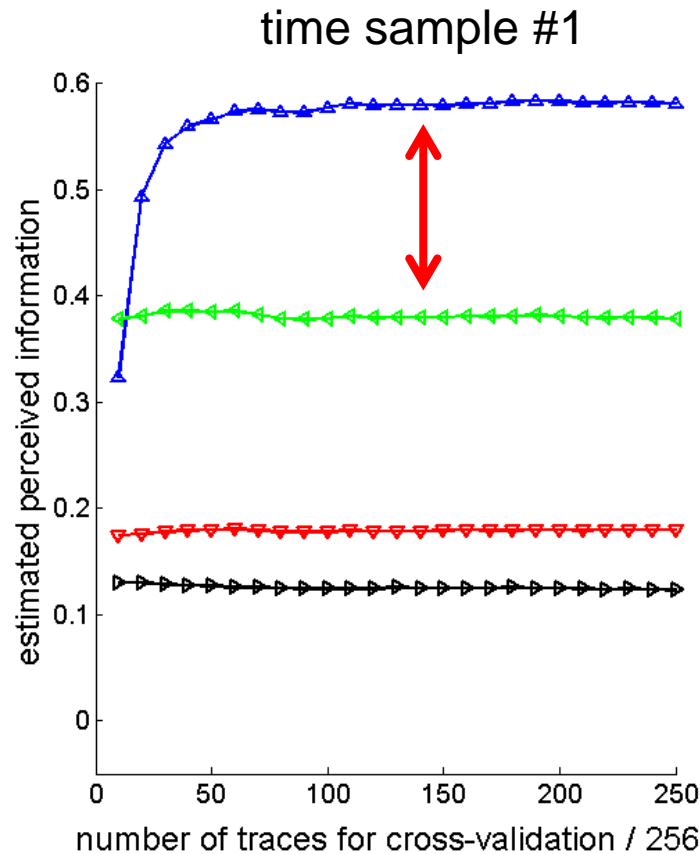
---



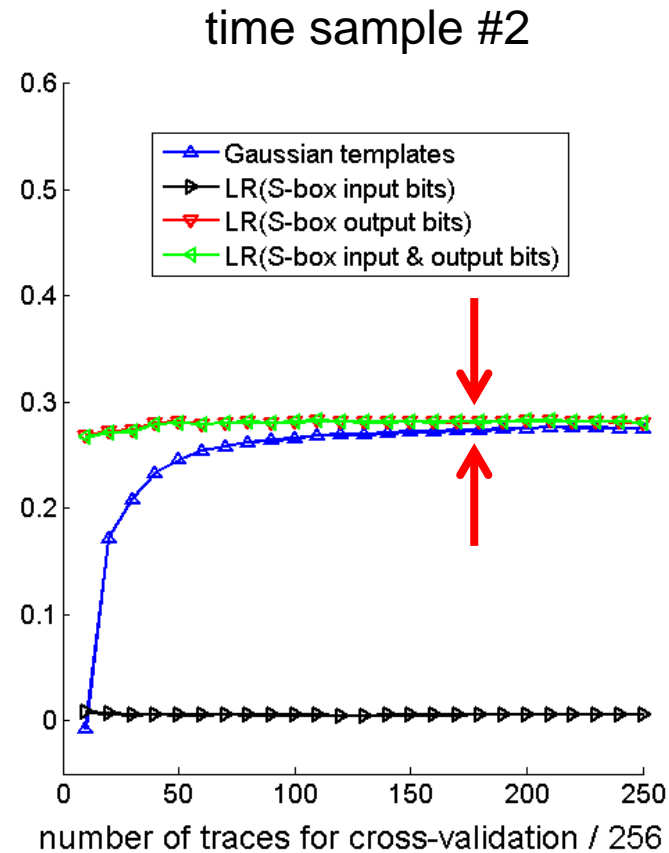
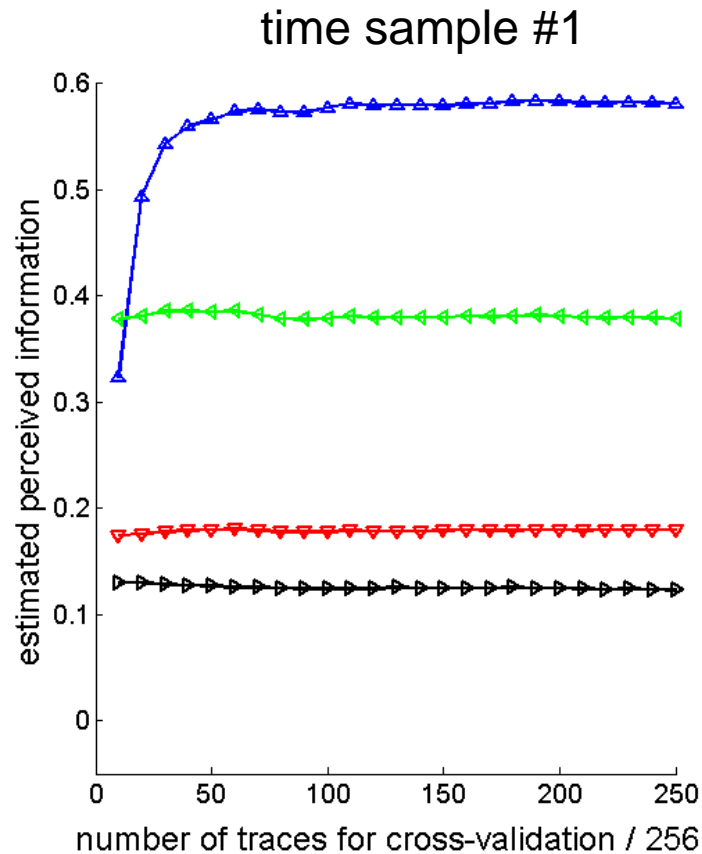
- Split traces in 10 (non-overlapping) sets, use  $9/10^{\text{th}}$  for profiling,  $1/10^{\text{th}}$  for estimating the PI
- Repeat 10 times to get average & spread

- Split traces in 10 (non-overlapping) sets, use 9/10<sup>th</sup> for profiling, 1/10<sup>th</sup> for estimating the PI
- Repeat 10 times to get average & spread
- Example of models
  - *Gaussian templates*: estimate one Gaussian distribution per value of  $x_i \oplus k_i$
  - *Linear regression*: approximate  $L(x_i, k_i)$  with a linear combination of basis elements
    - e.g. the S-box input & output bits

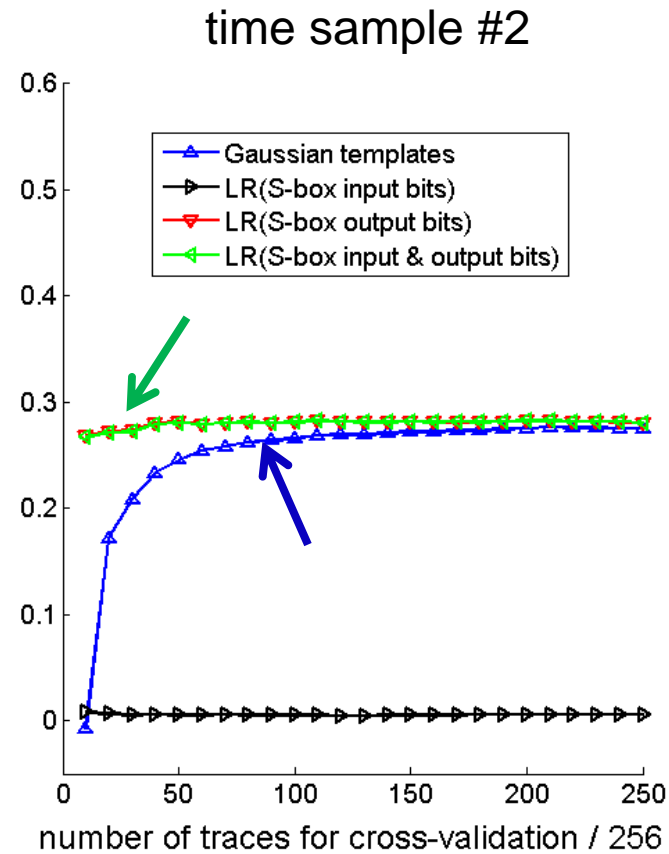
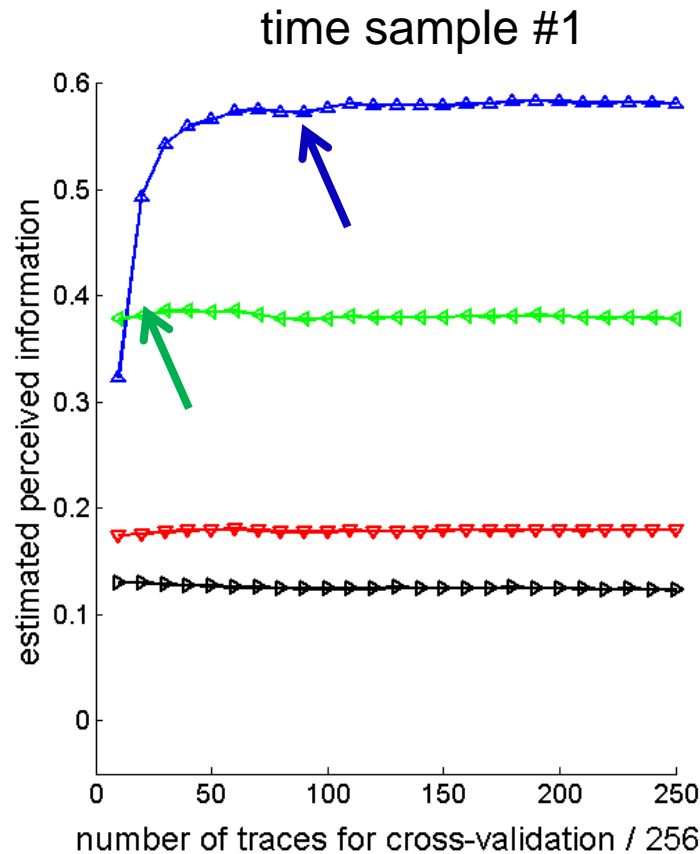




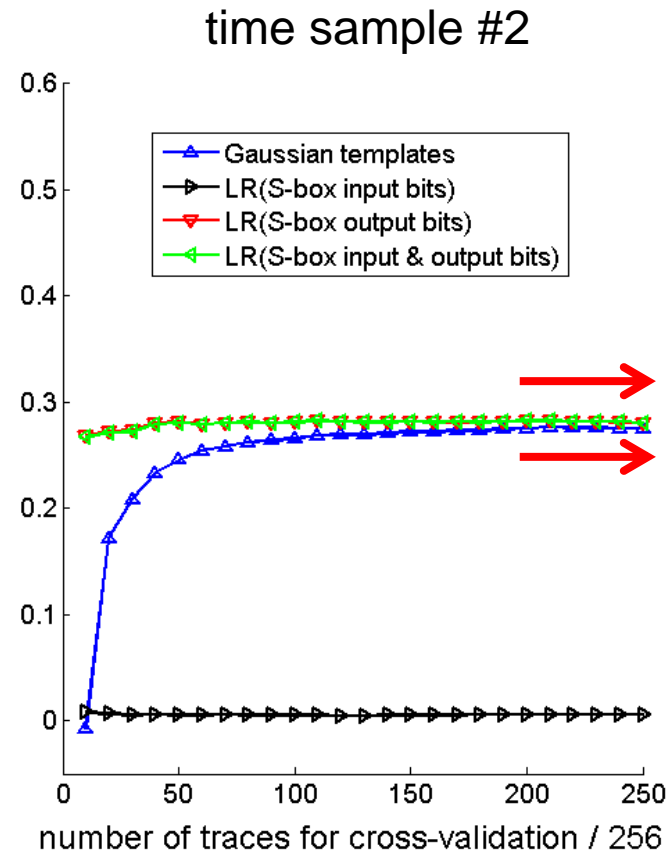
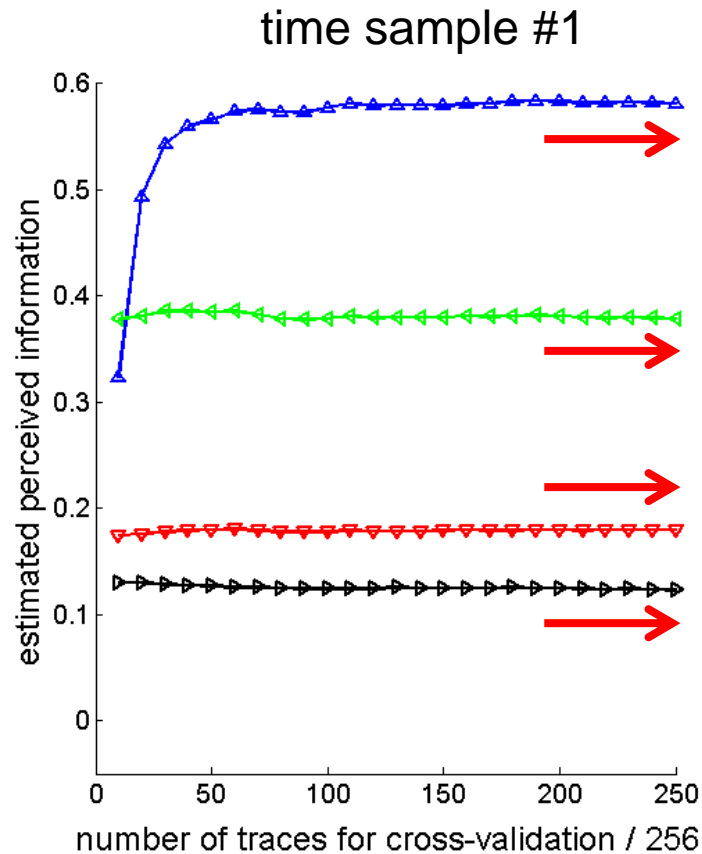
- Gaussian templates more informative for t1



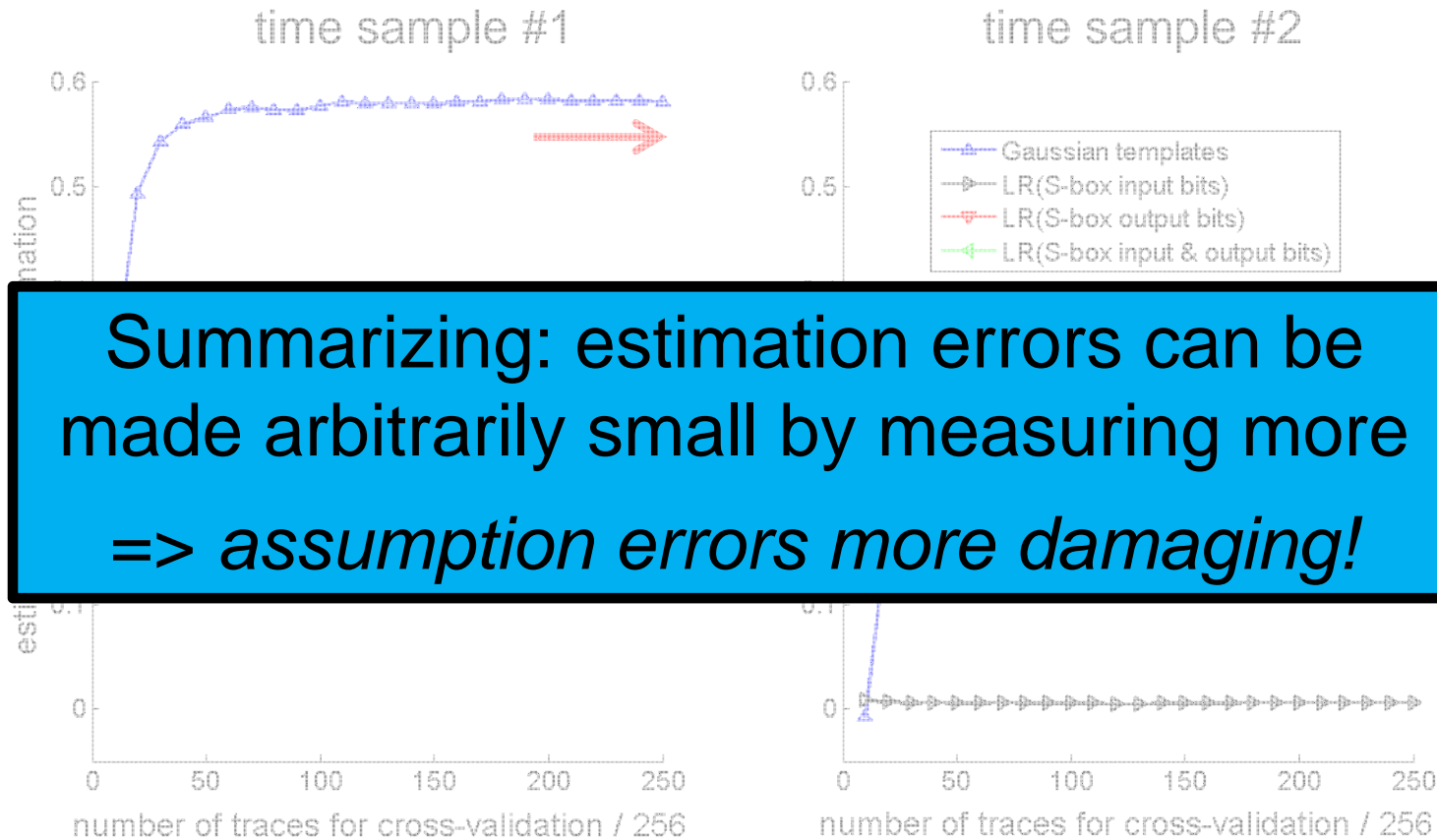
- Linear basis with S-box output bits sufficient for t2



- Estimation of Gaussian templates more expensive



- All models have converged after ~50,000 traces



- All models have converged after ~50,000 traces



---

Second question: assumption errors

***Is my model good enough?***

**(PART I: conditioned on the # of measurements)**

---

- Fact: two multidimensional distributions  $\mathcal{F}$  and  $\mathcal{G}$  are equal if the variables  $X \sim \mathcal{F}$  and  $Y \sim \mathcal{G}$  generate identical distributions for the distance  $D(.,.)$

- Fact: two multidimensional distributions  $\mathcal{F}$  and  $\mathcal{G}$  are equal if the variables  $X \sim \mathcal{F}$  and  $Y \sim \mathcal{G}$  generate identical distributions for the distance  $D(.,.)$
- We can compute the simulated distance

$$f_{sim}(d) = \Pr[L_1 - L_2 \leq d \mid L_1, L_2 \sim \widehat{\Pr}_{model}]$$

- Fact: two multidimensional distributions  $\mathcal{F}$  and  $\mathcal{G}$  are equal if the variables  $X \sim \mathcal{F}$  and  $Y \sim \mathcal{G}$  generate identical distributions for the distance  $D(.,.)$
- We can compute the simulated distance

$$f_{sim}(d) = \Pr[L_1 - L_2 \leq d \mid L_1, L_2 \sim \widehat{\Pr}_{model}]$$

- And the sampled distance

$$\hat{g}_N(d) = \Pr[l_1 - l_2 \leq d \mid l_1 \stackrel{N}{\leftarrow} \widehat{\Pr}_{model}, l_2 \stackrel{N}{\leftarrow} \Pr_{chip}]$$

- Fact: two multidimensional distributions  $\mathcal{F}$  and  $\mathcal{G}$  are equal if the variables  $X \sim \mathcal{F}$  and  $Y \sim \mathcal{G}$  generate identical distributions for the distance  $D(.,.)$

- We can compute the simulated distance

$$f_{sim}(d) = \Pr[L_1 - L_2 \leq d \mid L_1, L_2 \sim \widehat{\Pr}_{model}]$$

- And the sampled distance

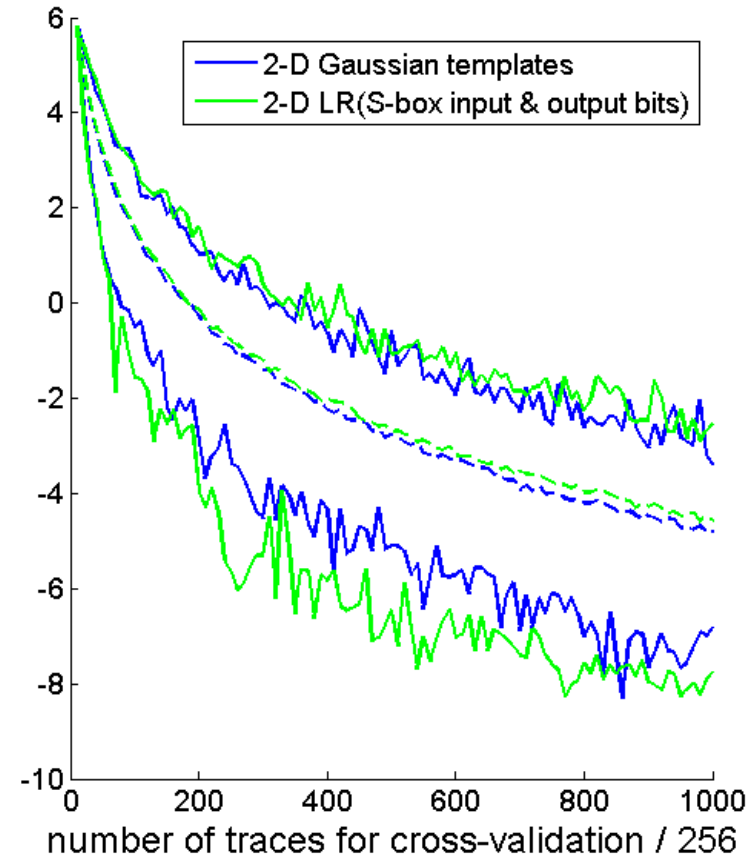
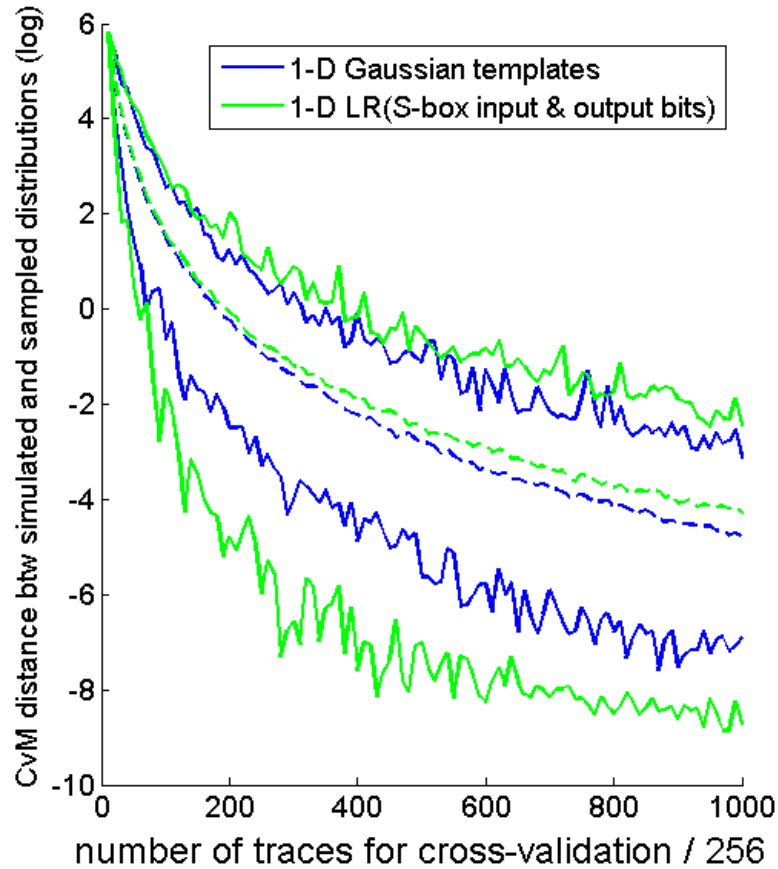
$$\hat{g}_N(d) = \Pr[l_1 - l_2 \leq d \mid l_1 \stackrel{N}{\leftarrow} \widehat{\Pr}_{model}, l_2 \stackrel{N}{\leftarrow} \Pr_{chip}]$$

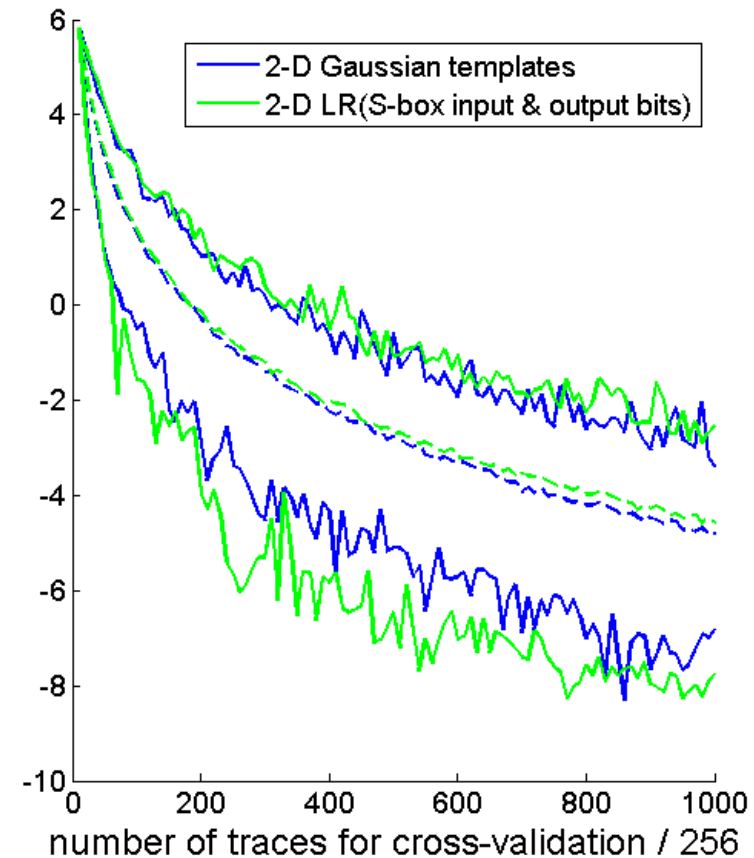
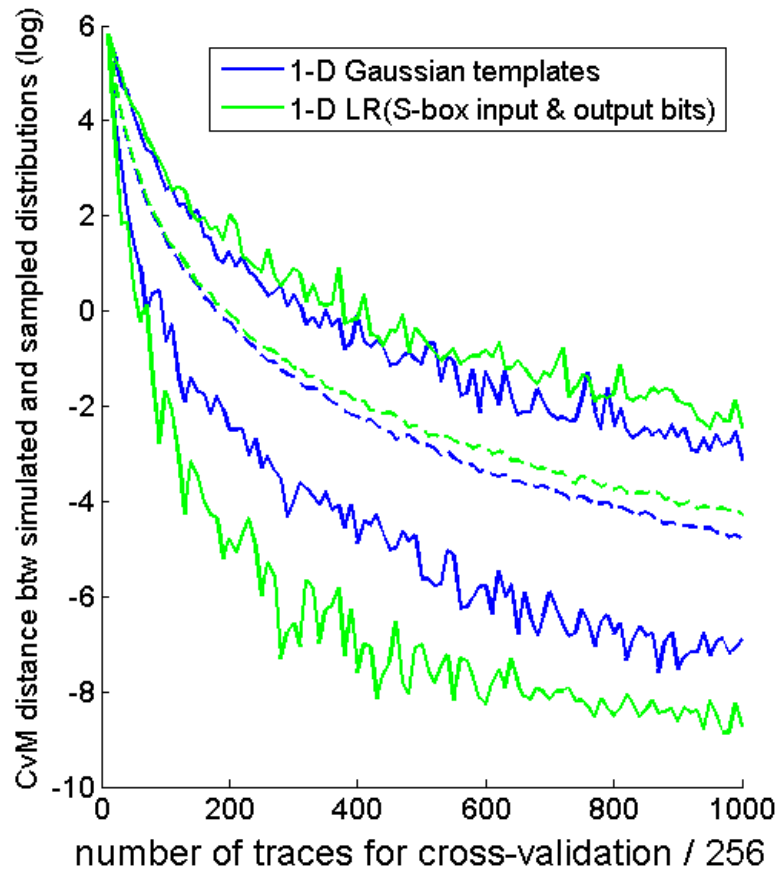
- And test their CvM divergence

$$\widehat{CvM}(f_{sim}, \hat{g}_N) = \int [f_{sim}(x) - \hat{g}_N(x)]^2 dx$$

# With cross-validation again, we obtain

11

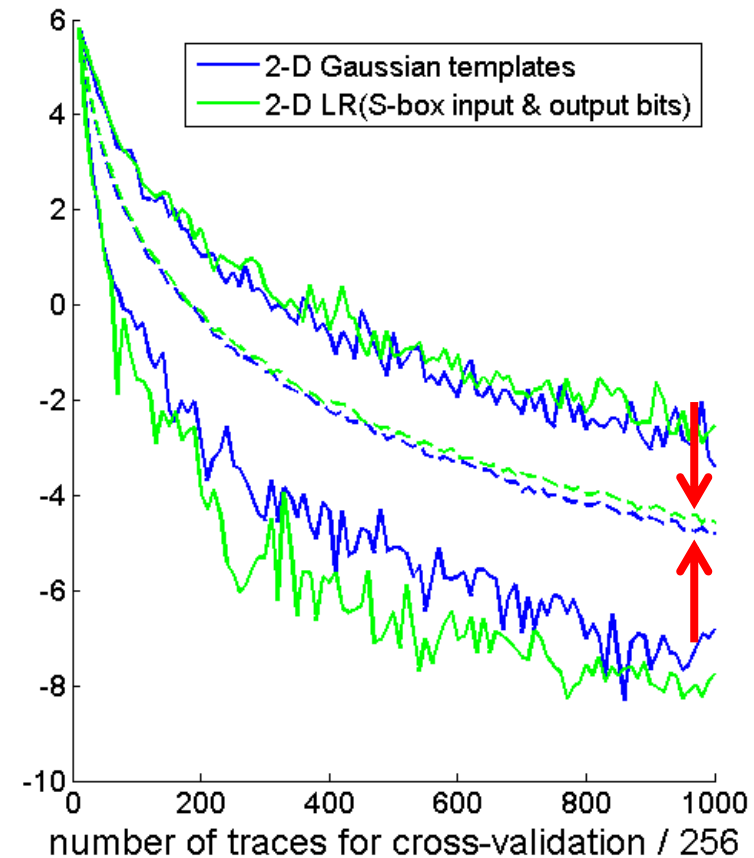
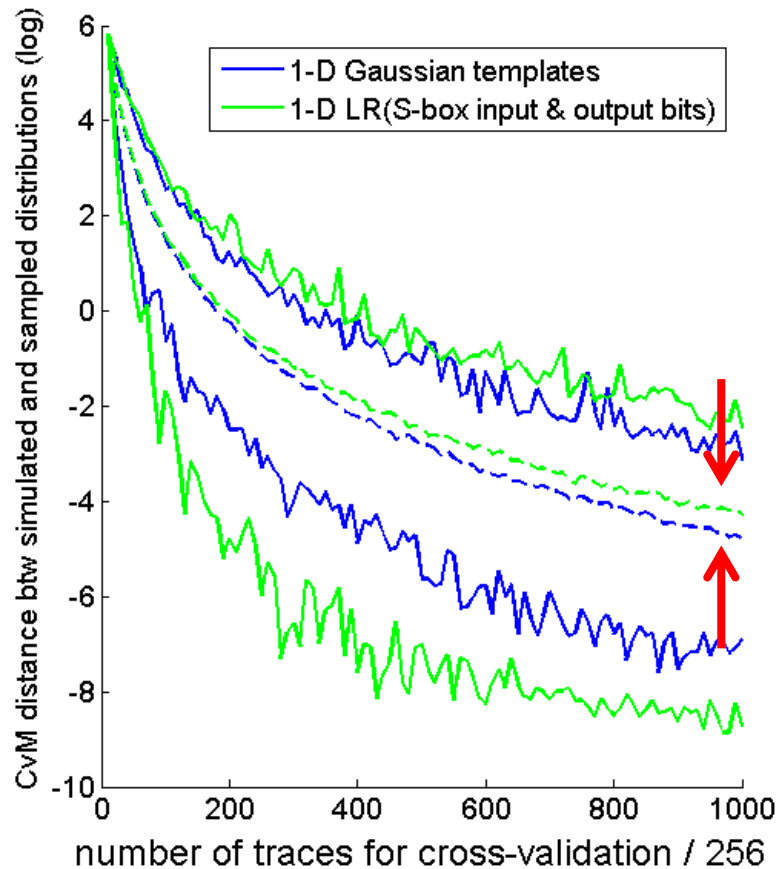




- Any incorrect assumption  $\Rightarrow$  CvM saturates

# With cross-validation again, we obtain

11



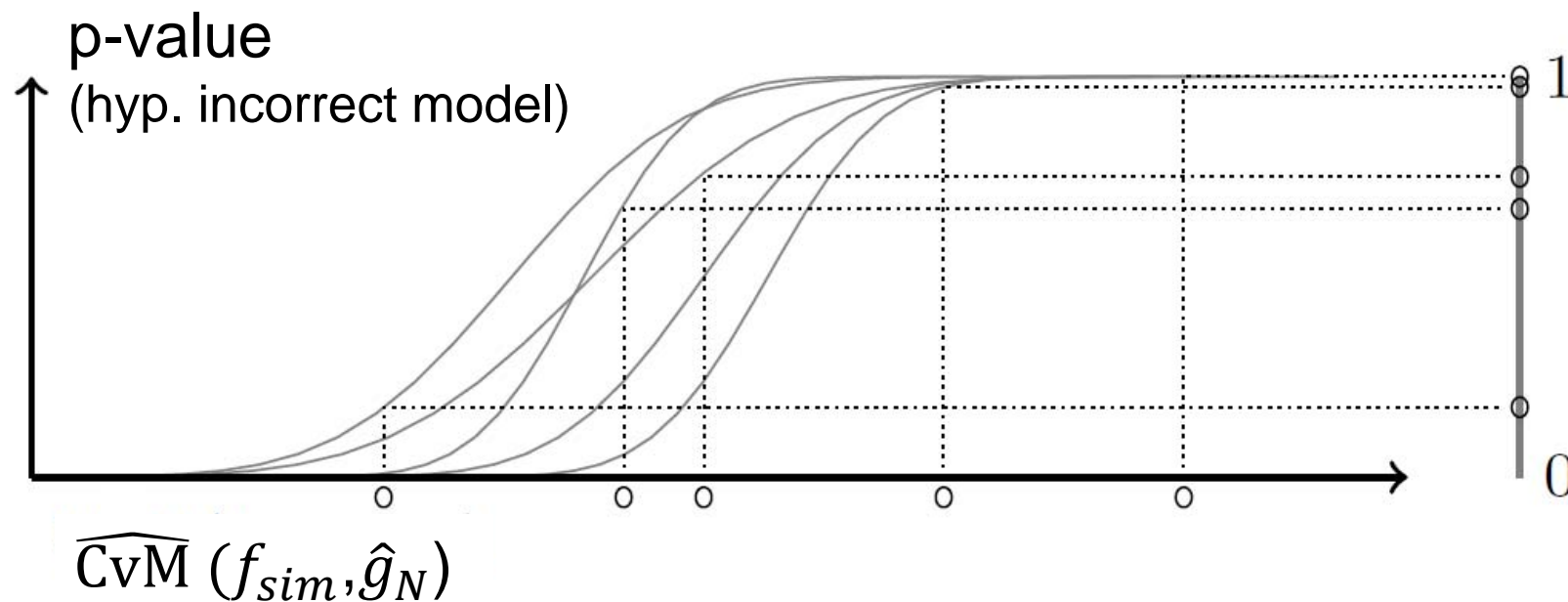
- Are these models already saturating?

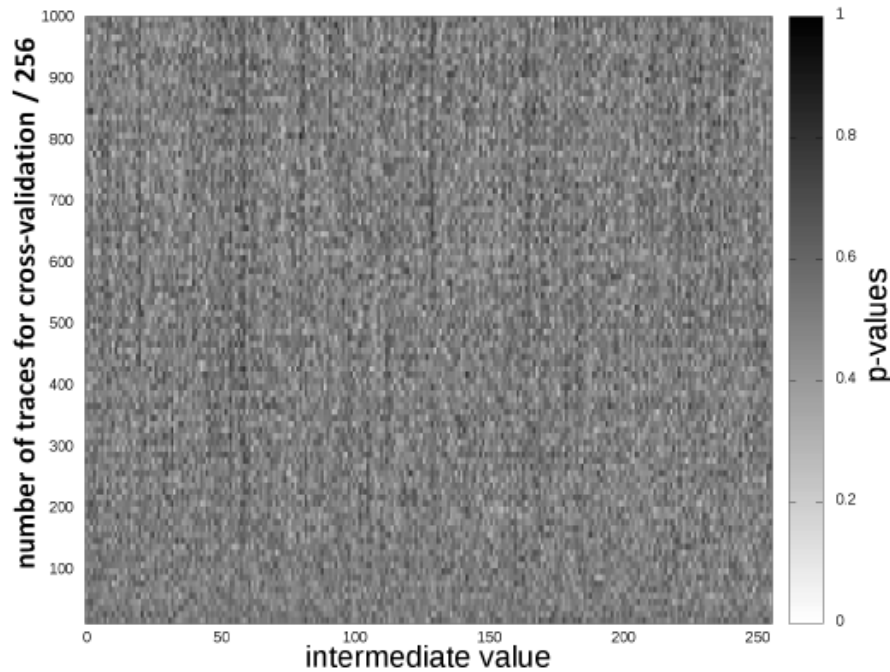


- Goal: try to detect when assumption errors become significant in front of estimation ones

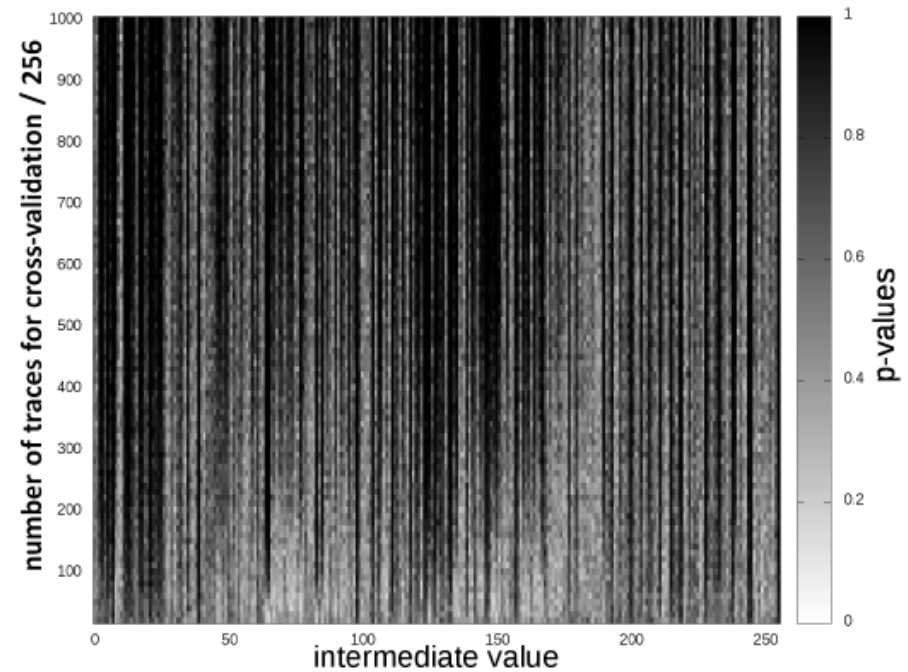
- Goal: try to detect when assumption errors become significant in front of estimation ones
- Characterize the probability that a given model error can be explained by estimation issues

- Goal: try to detect when assumption errors become significant in front of estimation ones
- Characterize the probability that a given model error can be explained by estimation issues

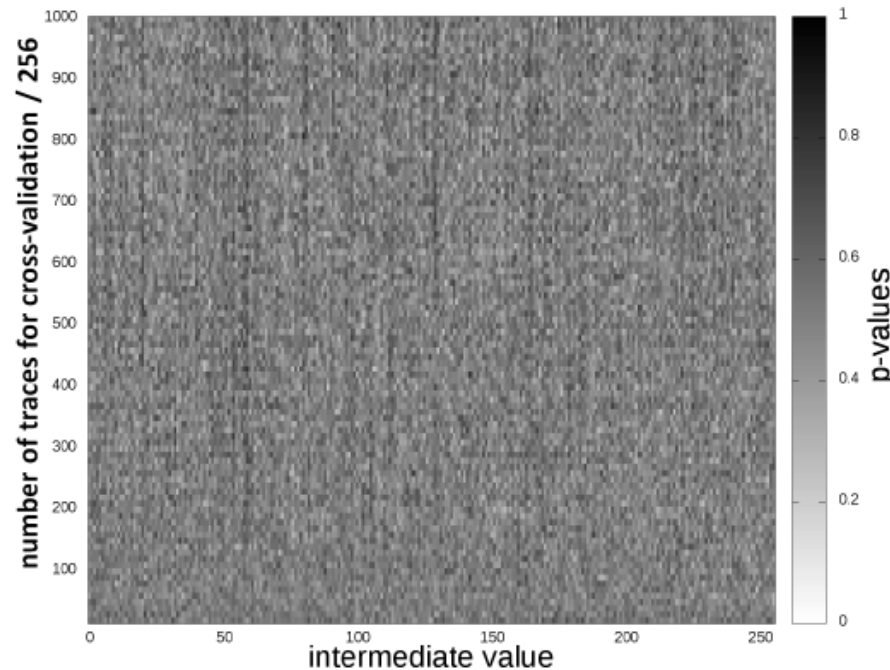




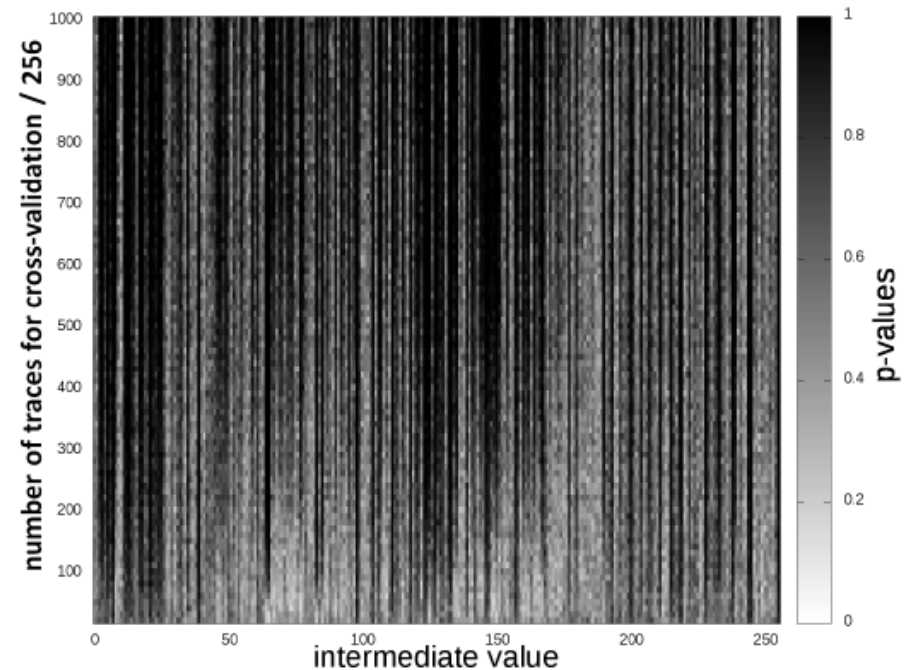
Gaussian templates



Linear regression



Gaussian templates



Linear regression

=> Gaussian templates are **good enough** with up to **256,000 traces** in the cross-validation set

---

Second question: assumption errors

***Is my model good enough?***

**(PART II: independent of the # of measurements)**

---

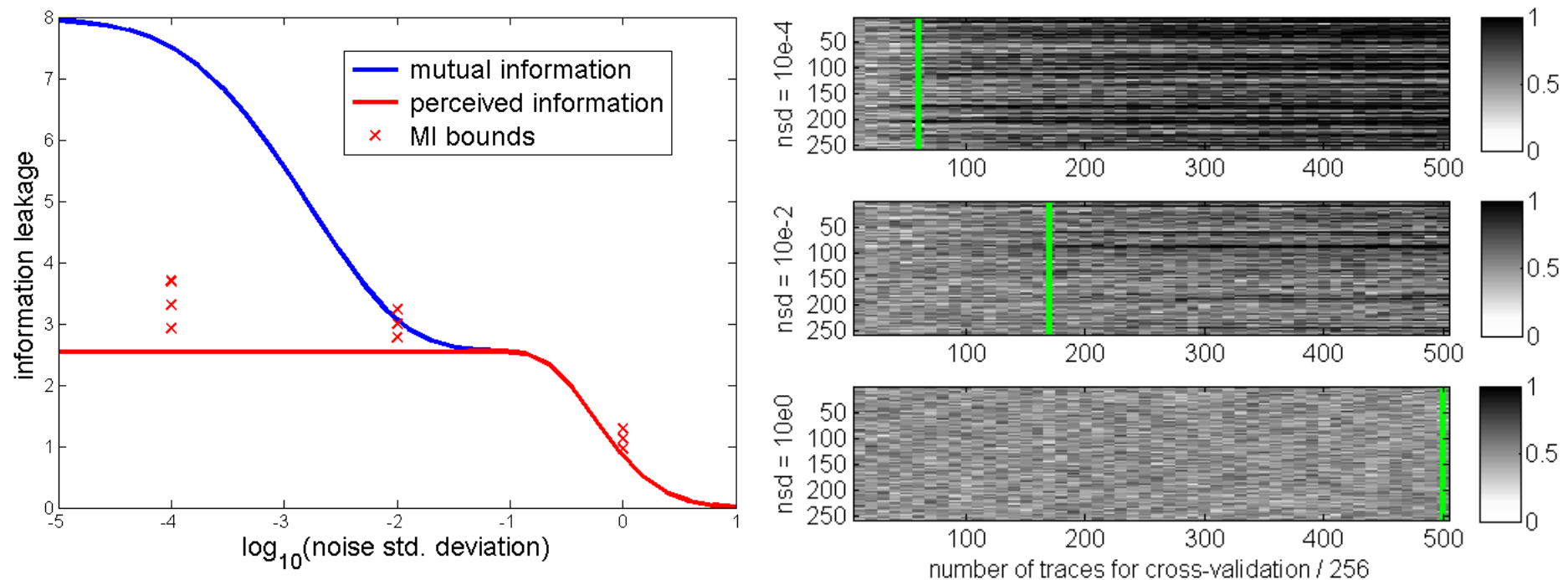
- Say we do measure up to the point where we detect assumption errors for all our models
- Can we bound the MI – PI difference?

- Say we do measure up to the point where we detect assumption errors for all our models
- Can we bound the MI – PI difference?
- Attempt: for  $N_{th}$  such that the assumption errors are not significant in front of estimation errors, try to “bound” the information loss by quantifying the (easier to compute) estimation error

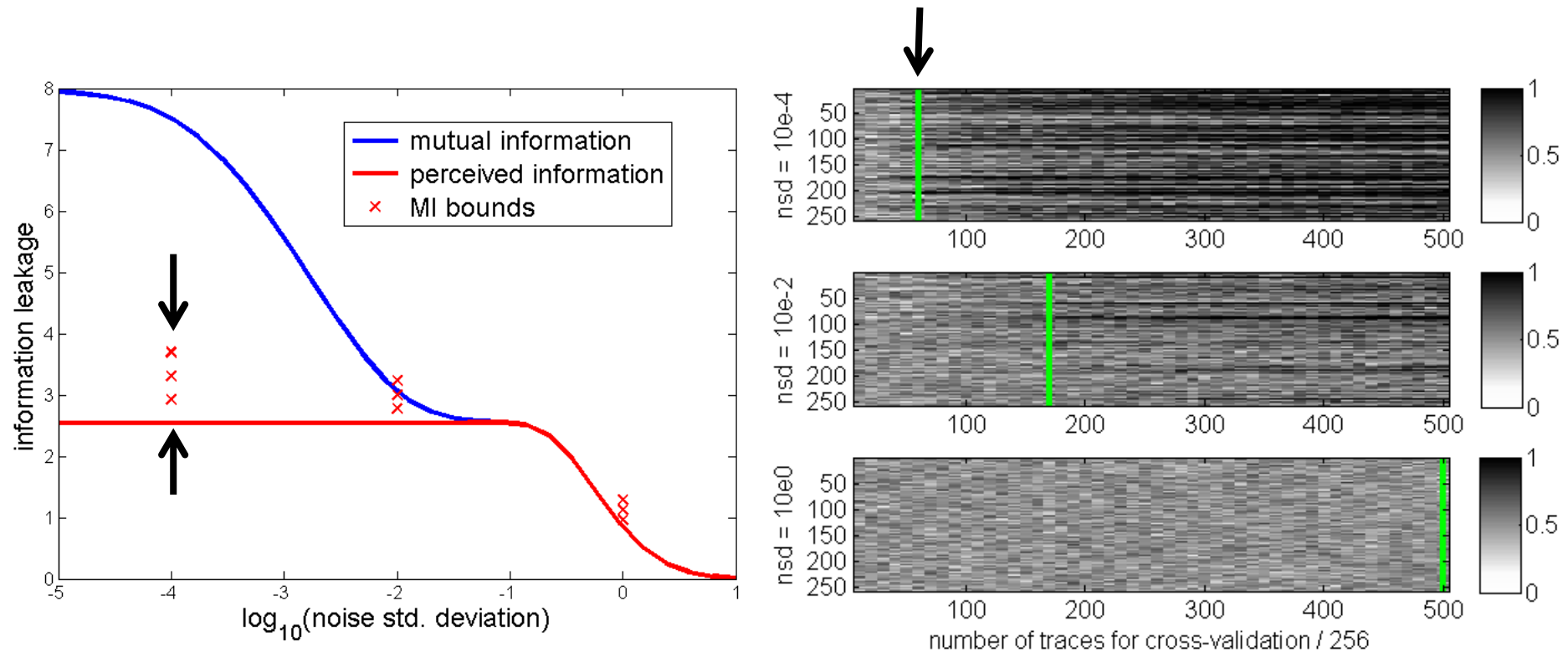


- Say we do measure up to the point where we detect assumption errors for all our models
- Can we bound the MI – PI difference?
- Attempt: for  $N_{th}$  such that the assumption errors are not significant in front of estimation errors, try to “bound” the information loss by quantifying the (easier to compute) estimation error
  - Hope: *assumption errors that are detected for smaller  $N_{th}$ 's should be larger in some sense*

- Mathematically generated leakages analyzed with LR (9-element basis) for different noise levels

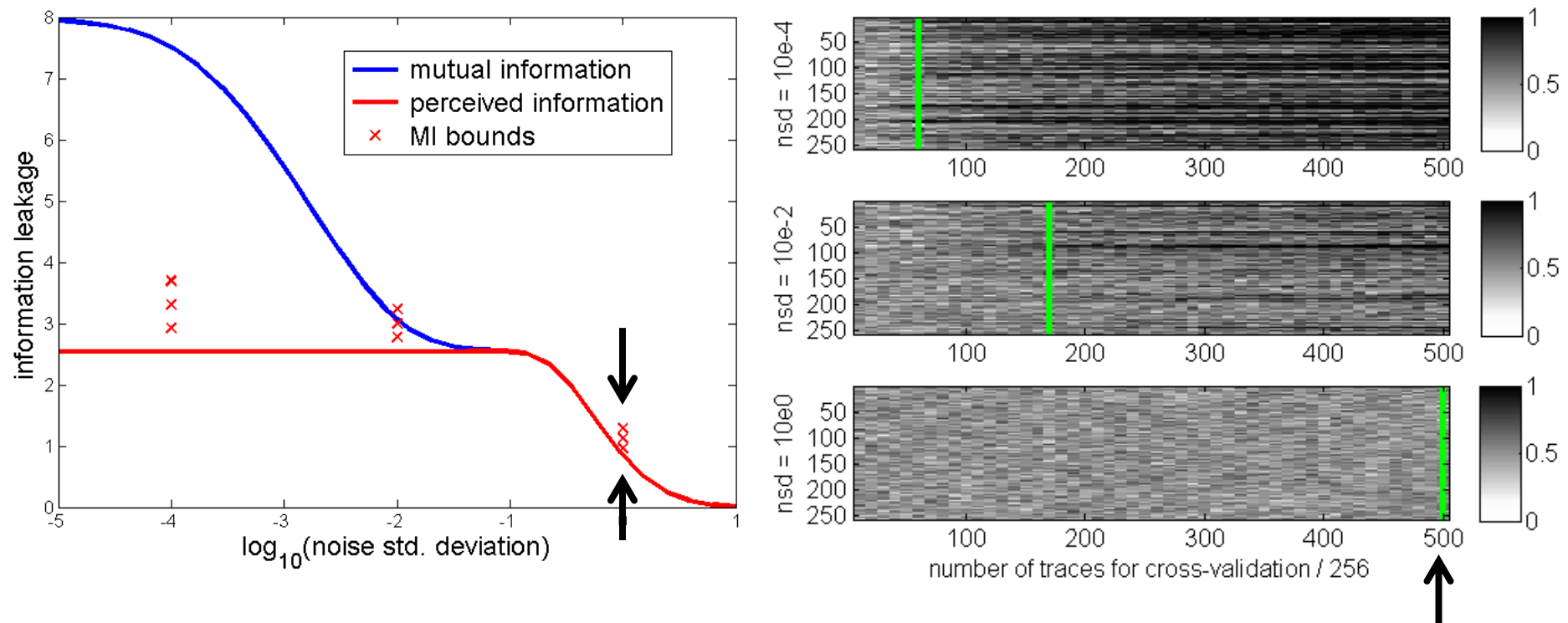


- Mathematically generated leakages analyzed with LR (9-element basis) for different noise levels



- Bound too optimistic for low noise levels

- Mathematically generated leakages analyzed with LR (9-element basis) for different noise levels



- Bound too *pessimistic* for *large* noise levels

- The threshold for which assumption errors are detected (e.g. average p-value) is hard to set independent of the leakage distributions

- The threshold for which assumption errors are detected (e.g. average p-value) is hard to set independent of the leakage distributions
- Information bounds anyway become pessimistic as the noise increases (since the noise then dominates the assumption errors in the MSE)

- The threshold for which assumption errors are detected (e.g. average p-value) is hard to set independent of the leakage distributions
- Information bounds anyway become pessimistic as the noise increases (since the noise then dominates the assumption errors in the MSE)

There could be more positive results for certain distributions (*scope for further research*), meanwhile...

- ***For a fixed number of measurements***  
(which is the case of all real-world evaluations)



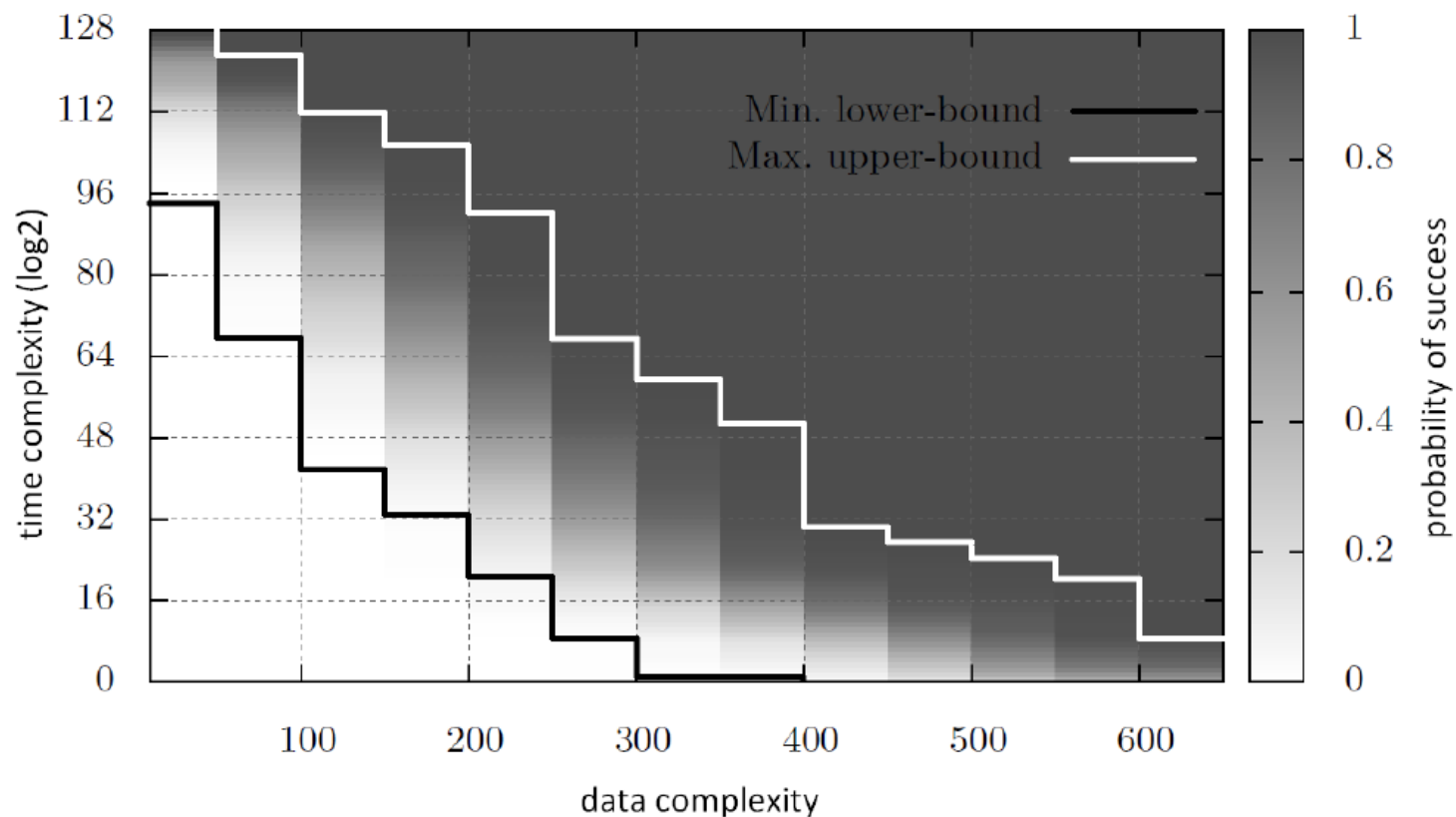
- ***For a fixed number of measurements***  
(which is the case of all real-world evaluations)
- *If assumption errors are detected:* the loss of information due to an imprecise model is significant (i.e. the model can be improved)

- ***For a fixed number of measurements***  
(which is the case of all real-world evaluations)
  - *If assumption errors are detected:* the loss of information due to an imprecise model is significant (i.e. the model can be improved)
  - *If assumption errors are not detected:* improving the model would not lead to better information extraction (since this improvement could not be distinguished due to the estimation errors)

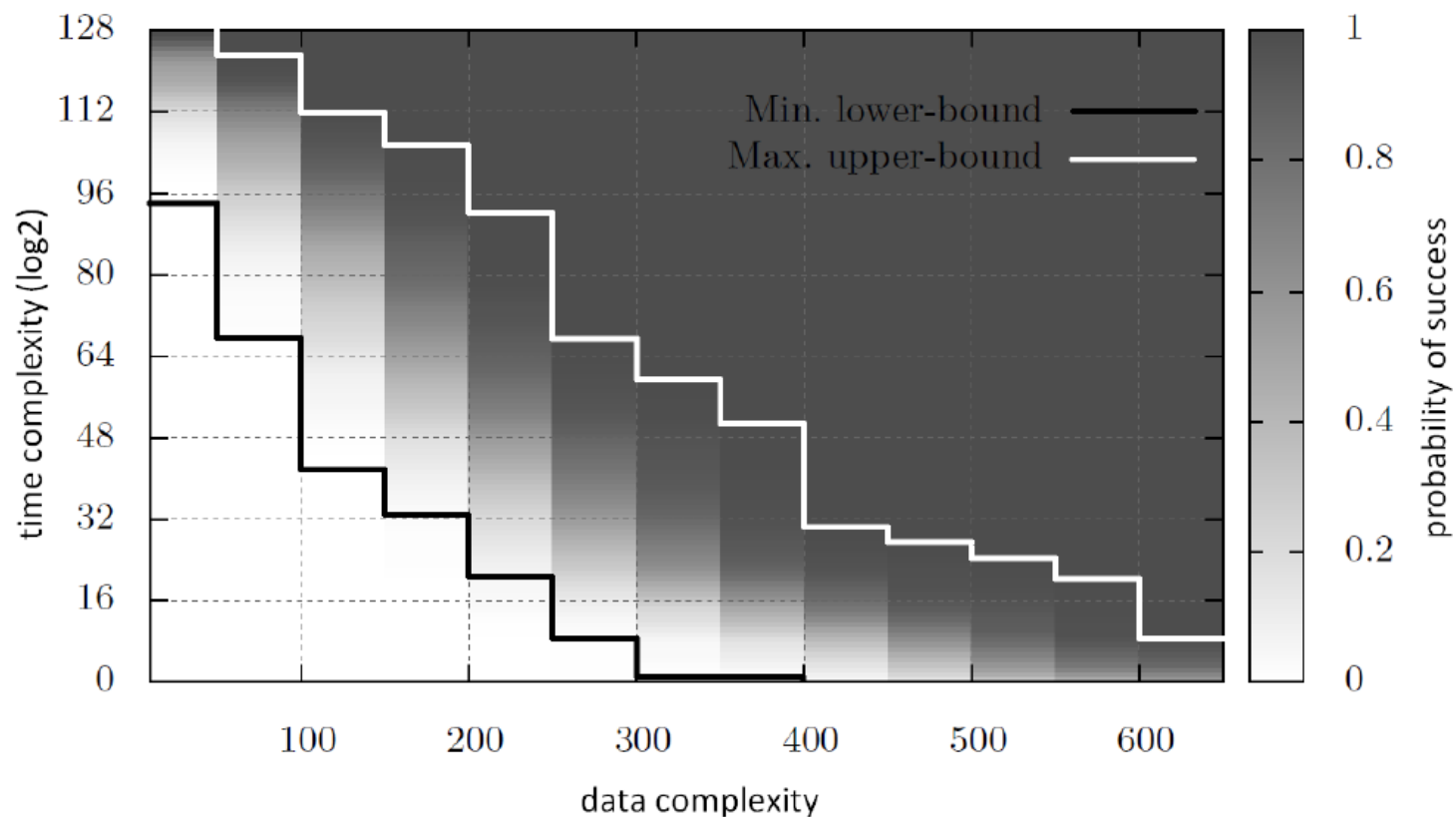
- *For a fixed number of measurements*  
(which is the case of all real-world evaluations)
  - *If assumption errors are detected:* the loss of information due to an imprecise model is significant (i.e. the model can be improved)
  - *If assumption errors are not detected:* improving the model would not lead to better information extraction (since this improvement could not be distinguished due to the estimation errors)
- All bets are off if more measurements are taken...

- Given a leakage model, it is pretty straightforward to compute security metrics (success probability)

- Given a leakage model, it is pretty straightforward to compute security metrics (success probability)



- Given a leakage model, it is pretty straightforward to compute security metrics (success probability)



- Closer to the  $\epsilon$ 's in proofs of leakage-resilience

Main message:

- Strict bounds on the information leakage are hard to obtain in general (independent of the distributions and number of measurements)
- But given a number of measurements, we can be sure that a model is “good enough” (or not)

Main message:

- Strict bounds on the information leakage are hard to obtain in general (independent of the distributions and number of measurements)
- But given a number of measurements, we can be sure that a model is “good enough” (or not)
- Quite general problem (not limited to side-channel attacks): applies to any attempt to model an unknown physical or biological process



# THANKS

<http://perso.uclouvain.be/fstandae/>

1. F.-X. Standaert, T.G. Malkin, M. Yung, *A Unified Framework for the Analysis of Side-Channel Key Recovery Attacks*, in the proceedings of Eurocrypt 2009, Lecture Notes in Computer Science, vol 5479, pp 443-461, Cologne, Germany, April 2009, Springer.
2. M. Renaud, F.-X. Standaert, N. Veyrat-Charvillon, D. Kamel, D. Flandre, *A Formal Study of Power Variability Issues and Side-Channel Attacks for Nanoscale Devices*, in the proceedings of Eurocrypt 2011, Lecture Notes in Computer Science, vol 6632, pp 109-128, Tallinn, Estonia, May 2011, Springer.
3. N. Veyrat-Charvillon, B. Gerard, F.-X. Standaert, *Security Evaluations Beyond Computing Power: How to Analyze Side-Channel Attacks you Cannot Mount?*, to appear in the proceedings of Eurocrypt 2013, Lecture Notes in Computer Science, vol 7881, pp 126-141, Athens, Greece, May 2013, Springer.